

Notice of References Cited	Application/Control No. 10/554,707		Applicant(s)/Patent Under Reexamination ONODERA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0096149 A1	05-2003	Koyama et al.	429/33
*	B	US-2003/0180596 A1	09-2003	Yoshimura et al.	429/33
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NON-PATENT DOCUMENTS

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	U	
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